



AGH UNIVERSITY OF SCIENCE
AND TECHNOLOGY

Development of variable sampling rate low power 10-bit SAR ADC in 130 nm IBM technology

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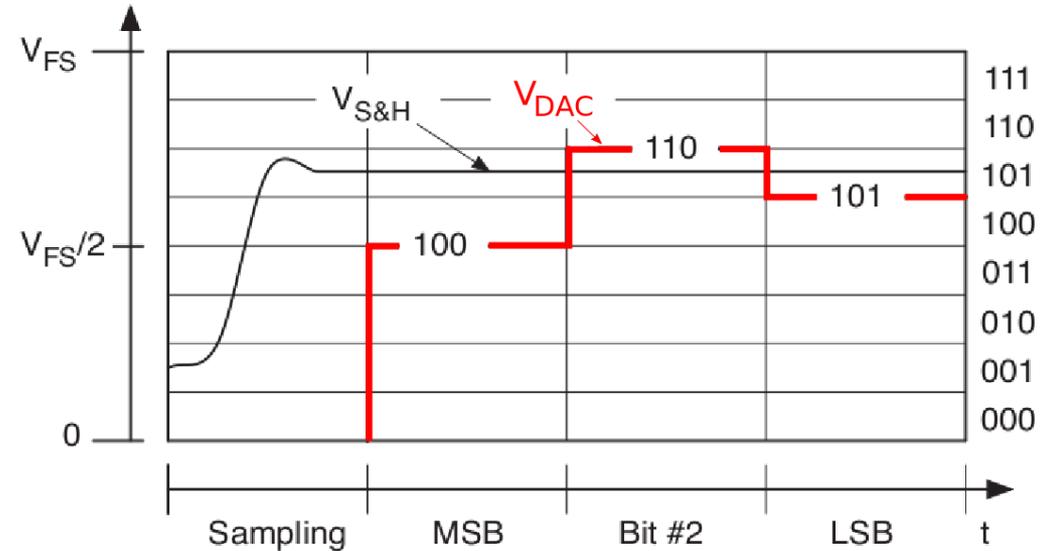
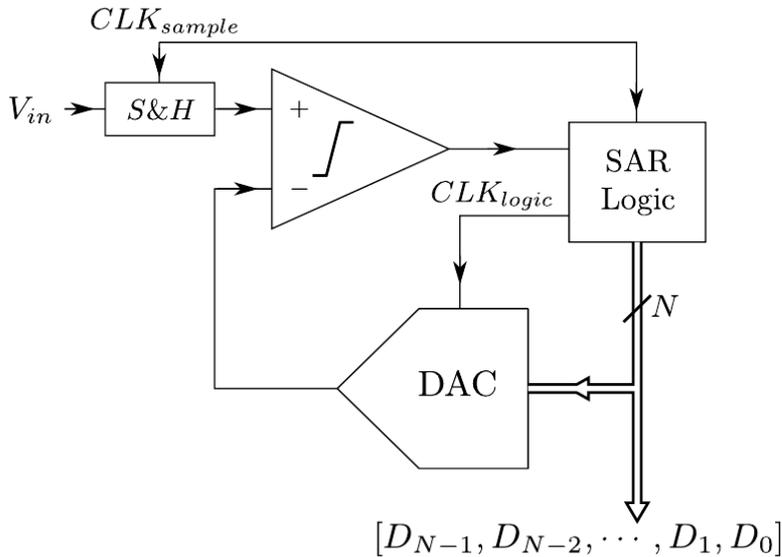
TWEPP Topical Workshop on Electronics for Particle Physics, 23 - 27 September 2013, Perugia, Italy

Agenda

- Successive Approximation Register (SAR) architecture
- Key aspects of DAC in SAR ADC:
 - Capacitance switching schemes
 - Split DAC architecture
- Design of SAR ADC
- Performance measurements of prototype ADC:
 - Theory of dynamic measurements
 - Measurement setup
 - Results of static and dynamic measurements
- Summary and future plans

SAR architecture

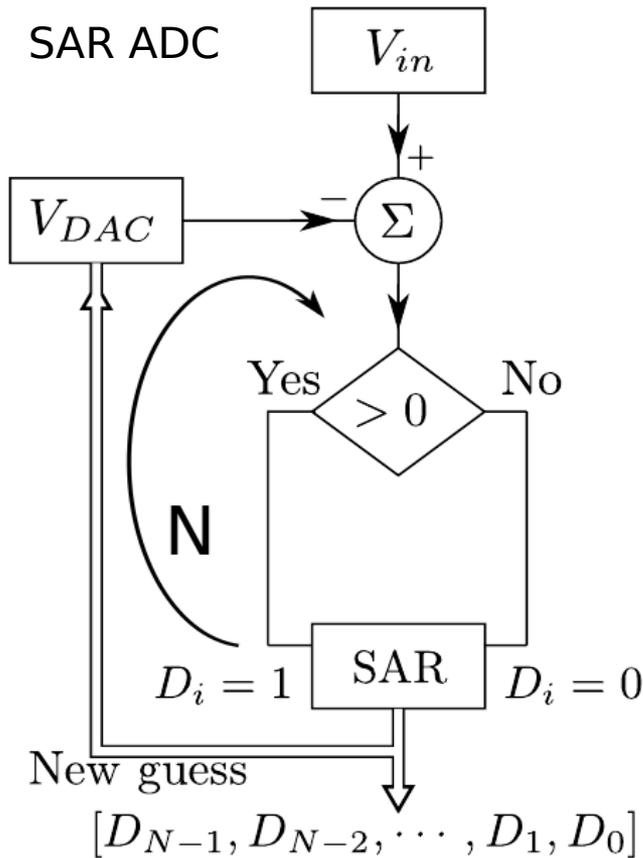
Fundamentals of operation



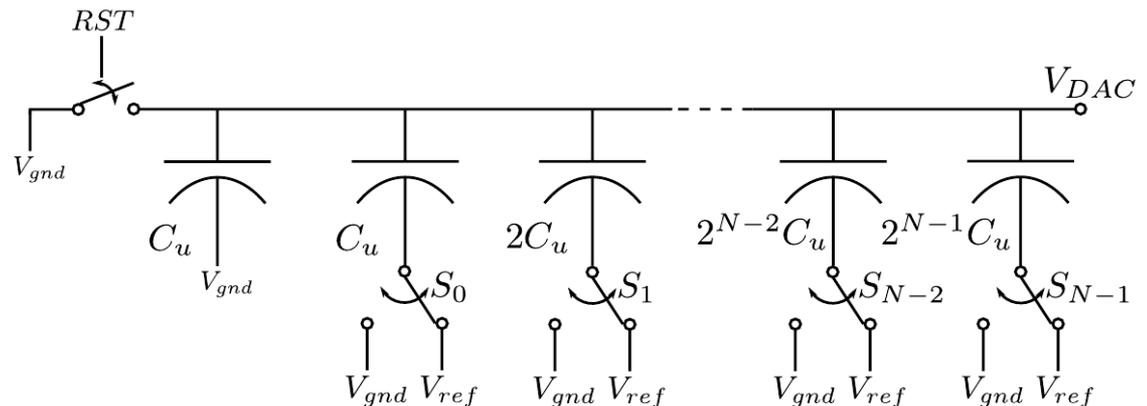
- Comparison between sampled input voltage and reference DAC output voltage
- Comparison result \rightarrow change reference DAC output voltage closer to input sample
- Each consecutive voltage change is half of the previous one
- Operation is repeated N times for N-bit ADC

SAR architecture

Advantages and disadvantages



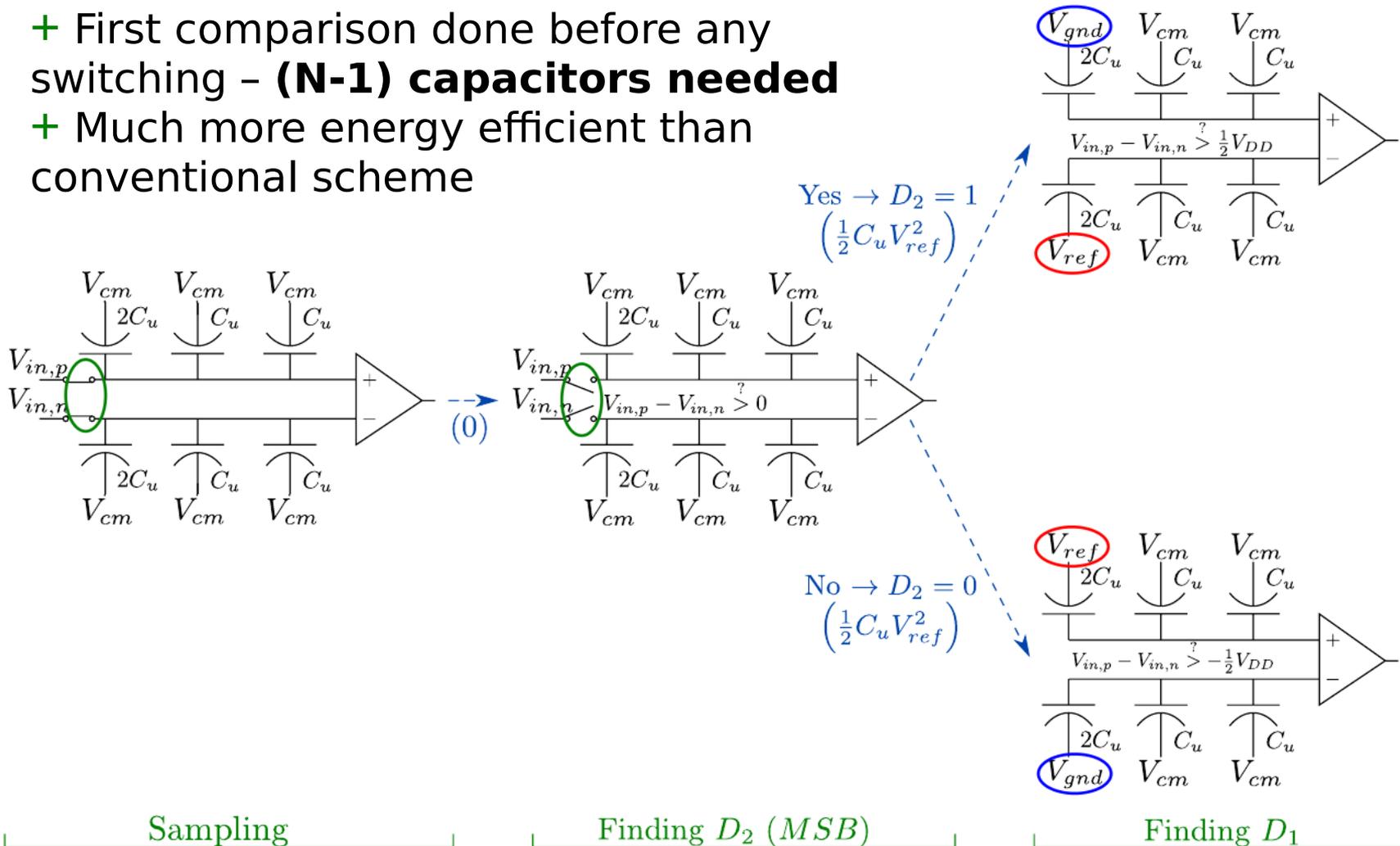
- + Power and area-efficient architecture - **same circuitry is used in loop N -times**
- + SAR ADC contains: single comparator, two DACs (differential) and SAR logic - **fits well to modern digital CMOS technologies**
- + DAC network is usually capacitive - **no static power, serves also as S/H circuit**



- Limited sampling rates - **but with modern CMOS technology ($\sim 100\text{nm}$) above 100MSps 10-bit ADCs are reported**

Key aspects of DAC in SAR ADC: Merged Capacitor Switching (MCS) scheme Chosen architecture

- + First comparison done before any switching - **(N-1) capacitors needed**
- + Much more energy efficient than conventional scheme



Key aspects of DAC in SAR ADC

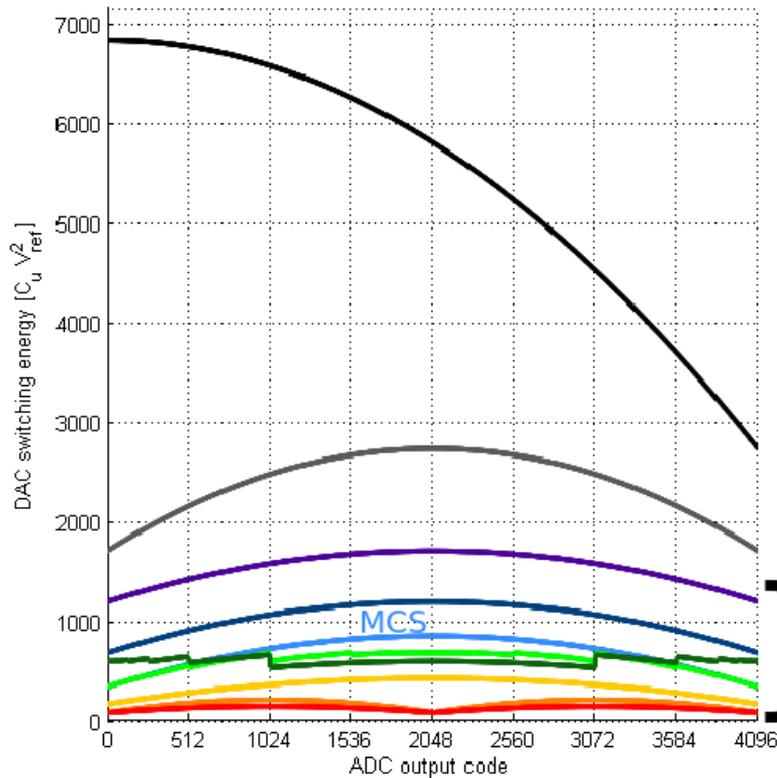
DAC switching energy:

Various SAR configurations.

- With CMOS technology scaling digital power consumption is decreasing rapidly - so minimizing analog power (DAC, comparator) is of main interest
- Huge progress has been obtained in the last ~10 years in optimizing capacitive DAC configurations and their switching schemes
- Various DAC switching configurations were proposed
 - **Conventional (100% power consumption)**
 - 2 step switching (~10% power saving)
 - Charge sharing (~24% power saving)
 - Split capacitor (~37% power saving)
 - Energy saving (~56% power saving)
 - Set and down (~81% power saving)
 - Vcm-based (~87% power saving)
 - **Merge Capacitor Switching (MCS) (~93% power saving)**
 - During the last year some new were proposed (up to ~98% power saving)

Key aspects of DAC in SAR ADC

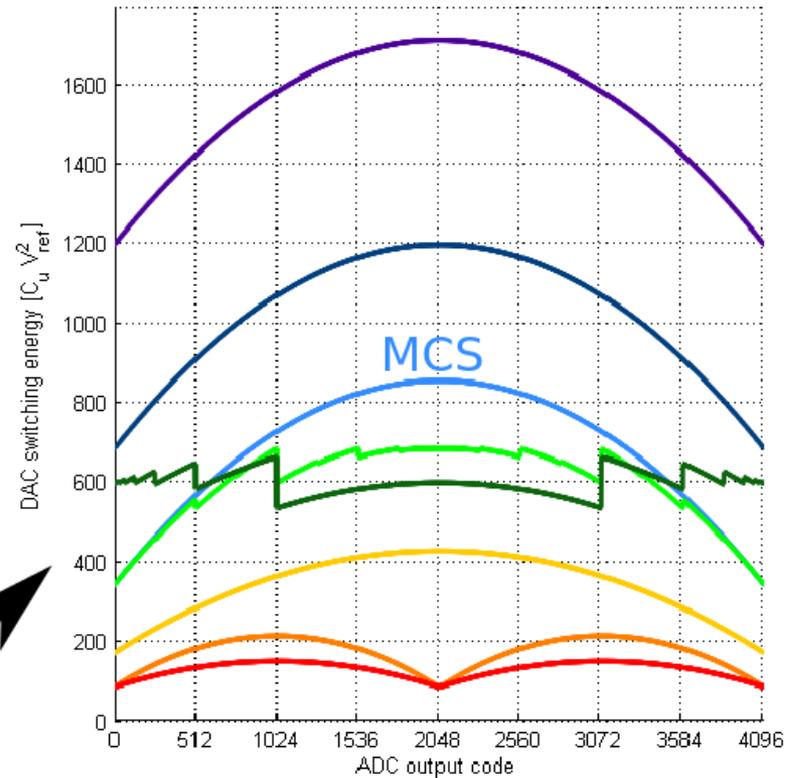
DAC switching energy: Switching scheme comparison



- classical ($E_{avg} = 5459.3[C_u V_{ref}^2]$)
- energy saving ($E_{avg} = 2388.3[C_u V_{ref}^2]$)
- switchback ($E_{avg} = 1535.5[C_u V_{ref}^2]$)

- monotonic ($E_{avg} = 1023.5[C_u V_{ref}^2]$)
- MCS ($E_{avg} = 682.2[C_u V_{ref}^2]$)**

Chosen scheme



- imp. switchback ($E_{avg} = 597.3[C_u V_{ref}^2]$)
- EMCS ($E_{avg} = 596.8[C_u V_{ref}^2]$)
- AMCS ($E_{avg} = 341.1[C_u V_{ref}^2]$)
- trilevel ($E_{avg} = 170.4[C_u V_{ref}^2]$)
- V_{CM} -based monotonic ($E_{avg} = 127.9[C_u V_{ref}^2]$)

Newly reported / variable common mode

Key aspects of DAC in SAR ADC

Capacitors noise and matching considerations

Noise

- Thermal switch noise of sampling circuit - kT/C

$$\frac{kT}{C} < \frac{\sigma^2}{12}, \sigma = \frac{V_{ref}}{2^N}$$

$$C > 12 kT \left(\frac{2^N}{V_{ref}} \right)$$

- For $V_{ref}=1$ V:

N=6 bits	$C >$	0.2 fF
N=8 bits	$C >$	3.3 fF
N=10 bits	$C >$	52.0 fF
N=12 bits	$C >$	830.0 fF

Switch noise is negligible

Matching

Capacitance density in IBM 130nm:

- VNCAP M1-M2 $\sim 0.4\text{fF}/\mu\text{m}^2$
- MIMCAP $\sim 2\text{fF}/\mu\text{m}^2$

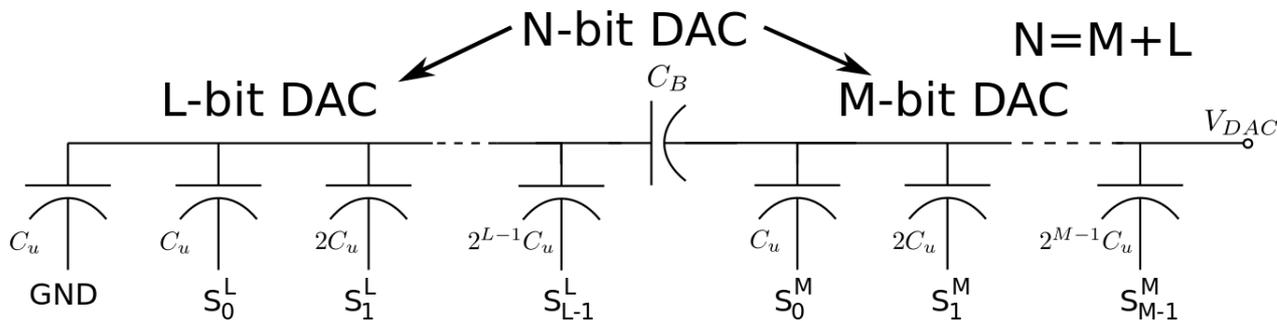
Mismatch (%) at 3σ :

- VNCAP $10 \times 20 \mu\text{m}^2$ ($\sim 80\text{fF}$): $\sim 5\%$
- MIMCAP $6 \times 7 \mu\text{m}^2$ ($\sim 80\text{fF}$): $\sim 0.7\%$
- MOM - no model exist, matching unknown...

MIMCAP has high density and good matching

Key aspects of DAC in SAR ADC

Splitted DAC



- N-bit DAC splitted into two DACs connected via series unit capacitor

- C_u - minimal unit capacitance ensuring 3σ matching within 0.5LSB
Technology limit - two 60fF capacitor in series - **30fF**

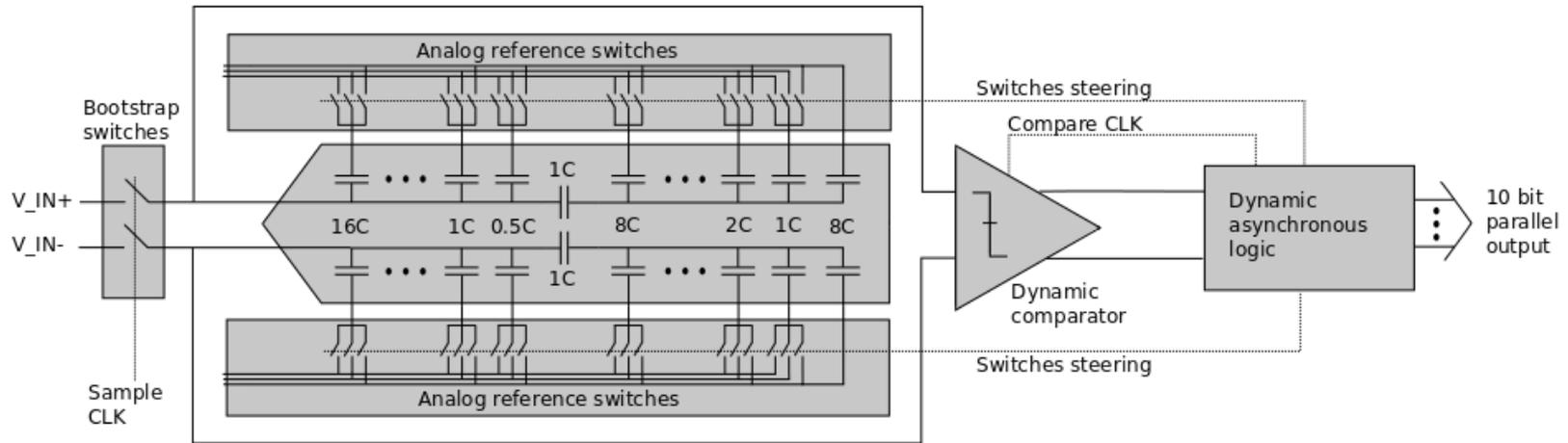
$$C_u = \frac{9}{2\sqrt{2}} 2^{2L} (2^M - 1) K_\sigma^2 K_C$$

$$K_\sigma = 4.12 \frac{\%}{\mu m} \quad K_C = 2.05 \mu m$$

M	L	C_u [fF]	C_{total} [pF]	No. of C_u	~Area [μm^2]
9	0	5.66 → 30	15.33	512	7079
8	1	11.29 → 30	7.65	257	3553
7	2	22.5 → 30	3.81	131	1811
6	3	44.64	2.81	71	1461
5	4	87.87	2.72	47	1903
4	5	170.07	2.55	47	3684
3	6	317.47	2.22	71	10388
2	7	544.24	1.63	131	32857
1	8	725.65	0.73	257	85947

Design of SAR ADC

Chosen architecture of 10-bit SAR ADC



Architecture of 10-bit ADC

- Differential segmented/split DAC with MCS switching scheme - **ultra low power**
- Dynamic comparator - **no static power consumption, power pulsing for free**
- Asynchronous logic - no clock tree - **power saving, allows asynchronous sampling**
- Dynamic SAR logic - **much faster than conventional static logic**

Design consideration:

- Variable sampling frequency (up to ~ 50 MS/s) and power consumption
- Power consumption 1-2 mW at 40 MS/s
- 146 μm pitch, ready for multichannel integration

Design of SAR ADC Dynamic comparator

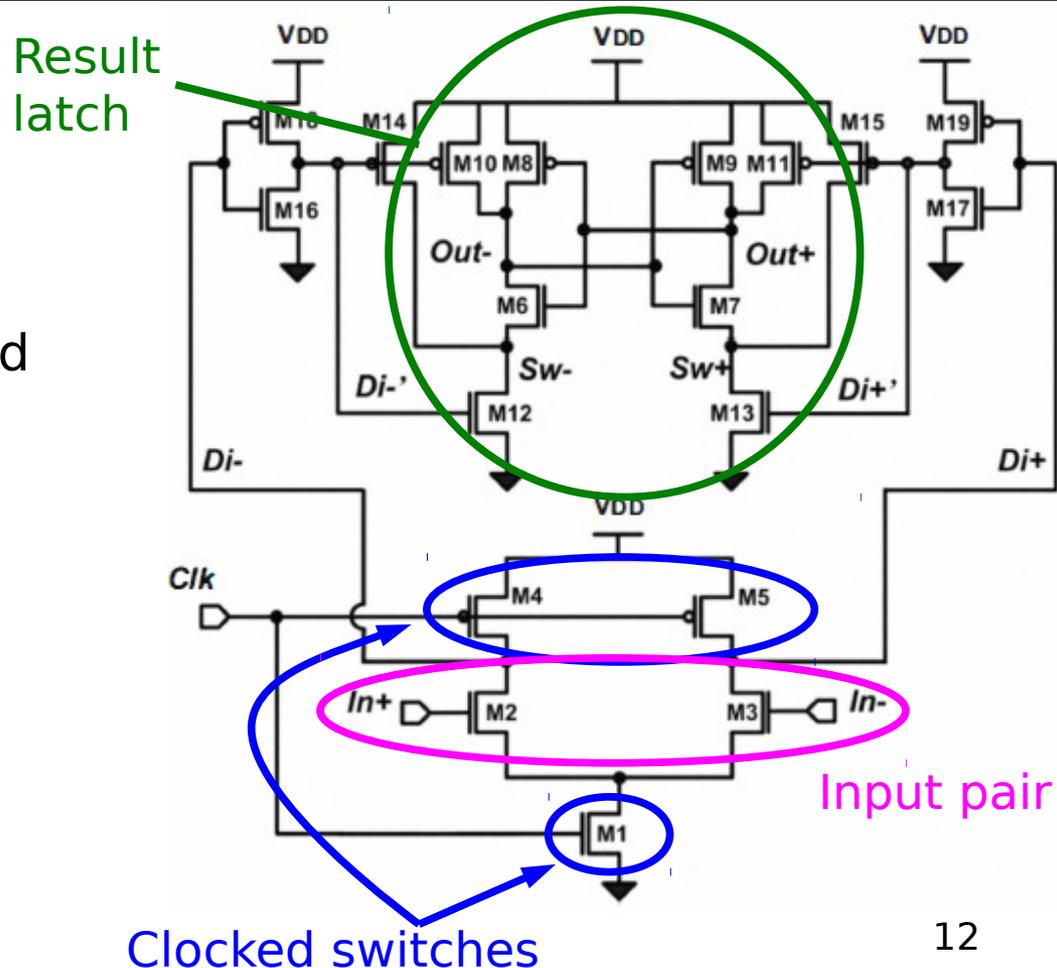
H.J. Jeon, Y-B. Kim, M. Choi "Offset voltage analysis of dynamic latched comparator", IEEE 54th Int. Midwest Symp. On Circuits and Systems, 2011

Dynamic comparator

- Comparison performed on rising edge of clock signal
- Reset (low clock level) needed before next comparison

Pros and cons:

- + No direct path current
- + Low power consumption
- Dead time needed for reset



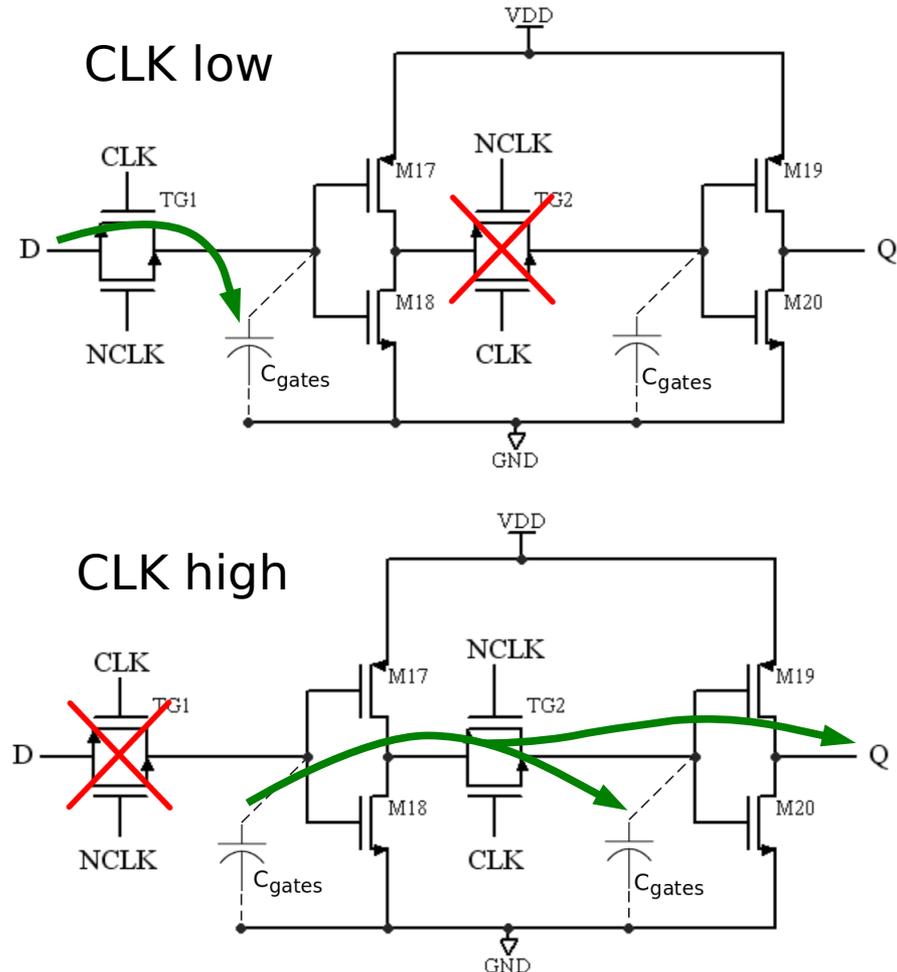
Design of SAR ADC

Dynamic logic - idea of operation

Dynamic D-type flip-flop:

- Bit (voltage level) stored on inverter gate capacitance
- + Very fast - only two small transistor gates need to be recharged on each clock slope
- Clock needs to run continuously (or static reset is needed)
- Manual layout

Flip-flop architecture	Signal propagation time [ps]	Power consumption [μ W/clock cycle]
Static	155	2.62
Dynamic	50	2.58

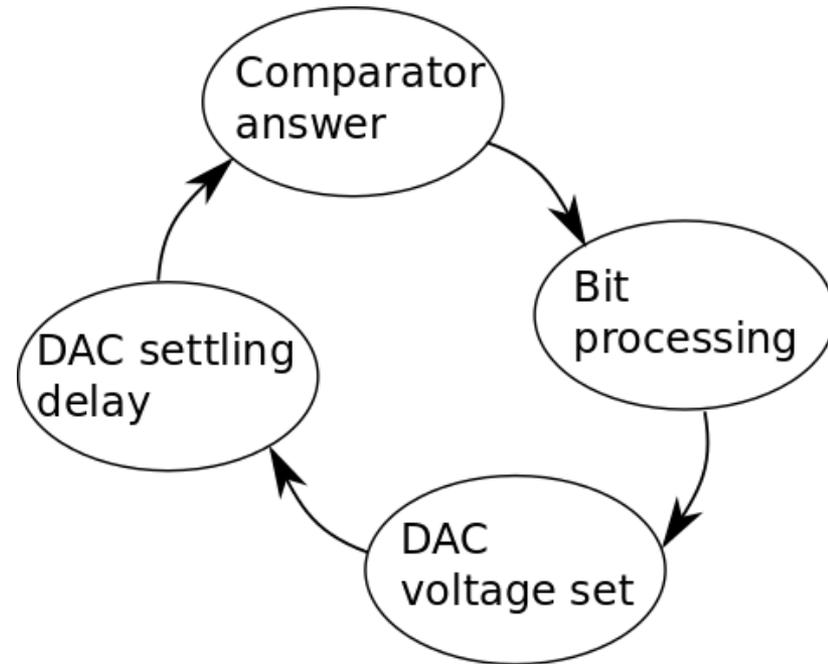


Dynamic flip-flop is 3 times faster

Design of SAR ADC

Asynchronous logic - no fast clock distribution

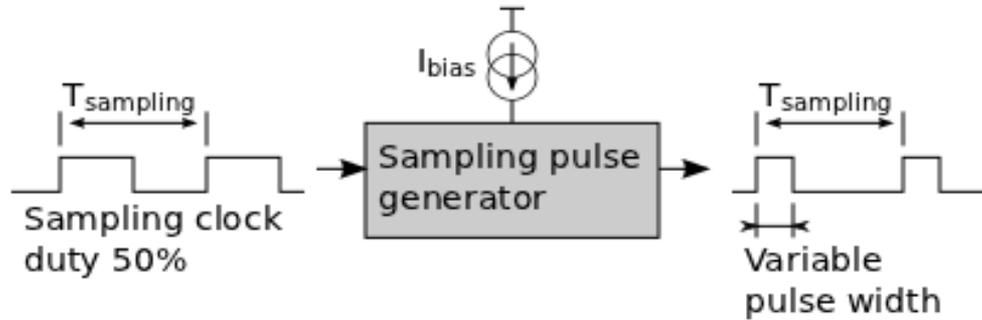
- To operate at 40MS/s 10-bit ADC have to convert single bit in approximately 2ns
- Each bit conversion require at least two clock cycles - generation and distribution of 1GHz clock is needed for synchronous operation
- Asynchronous logic → data flow releases actions in sequence



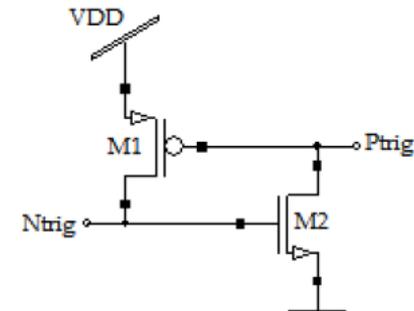
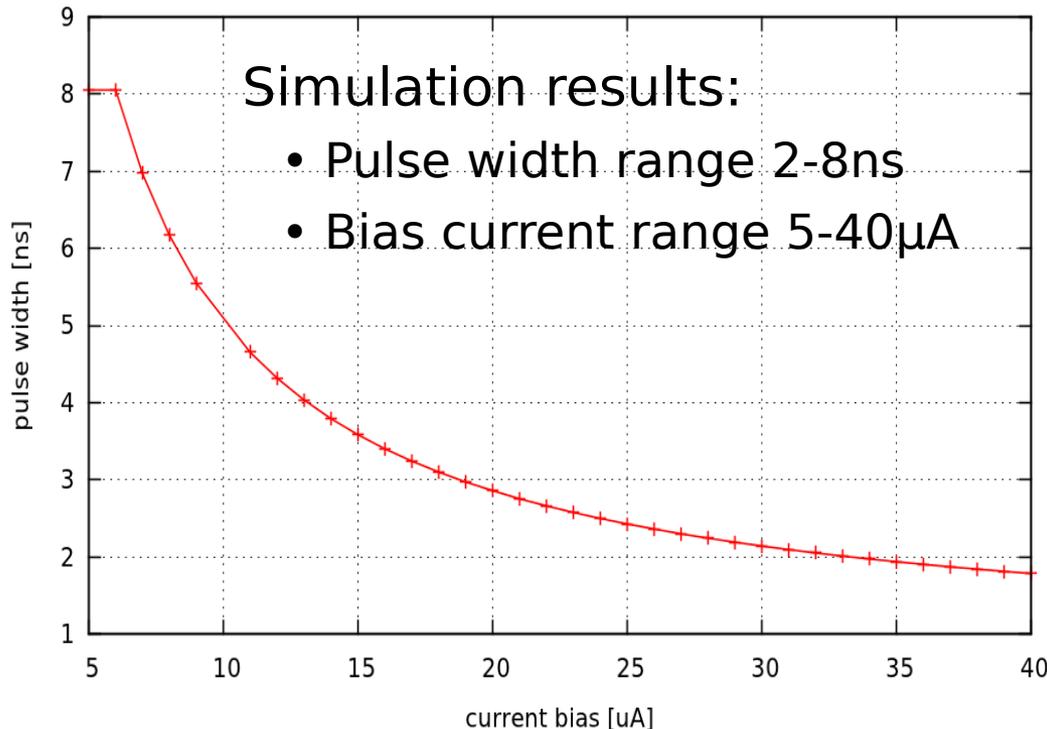
- + No fast clock distribution needed - a lot of power saved
- + Single slope of sampling signal starts the conversion → ADC can operate in **asynchronous mode**

Design of SAR ADC

Design of sampling pulse generator

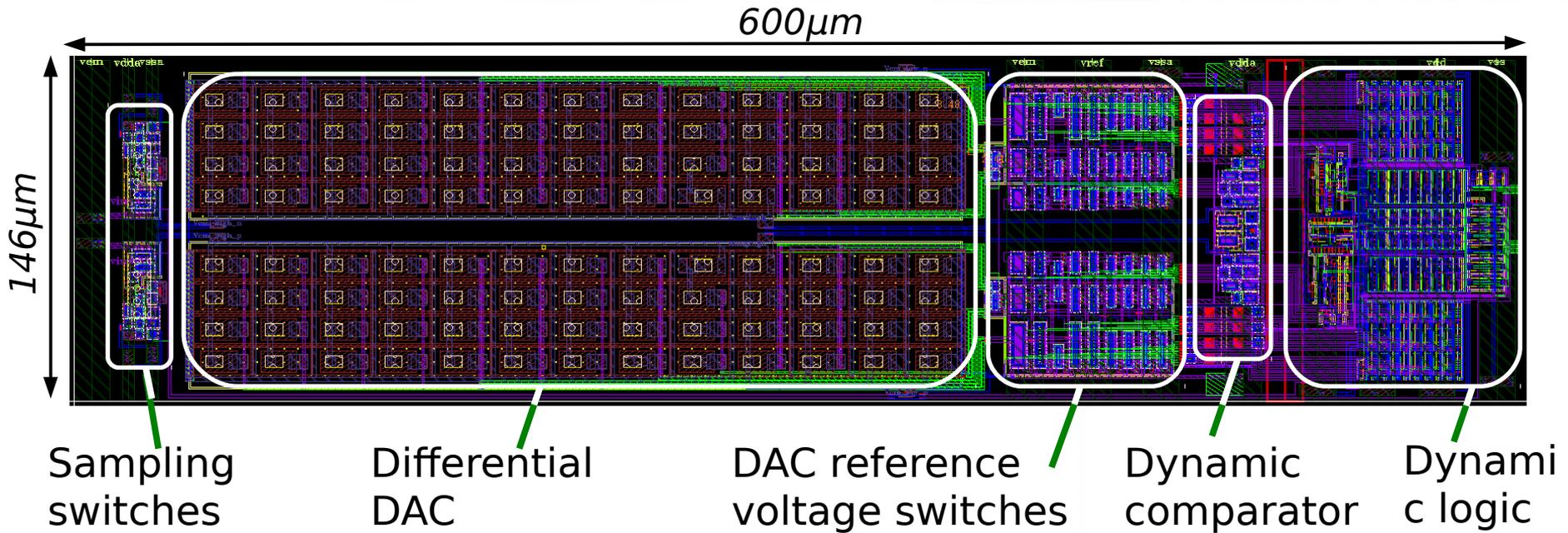


Generator of sampling pulse converts 50% duty external sampling clock into internal variable width pulse (controlled by I_{bias})

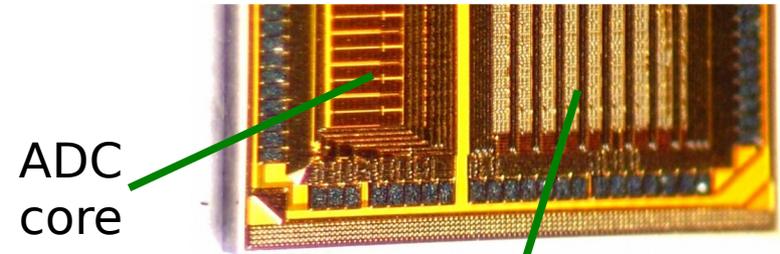


Pulse generator design is based on MOS thyristor delay circuit.

Design of SAR ADC Channel layout



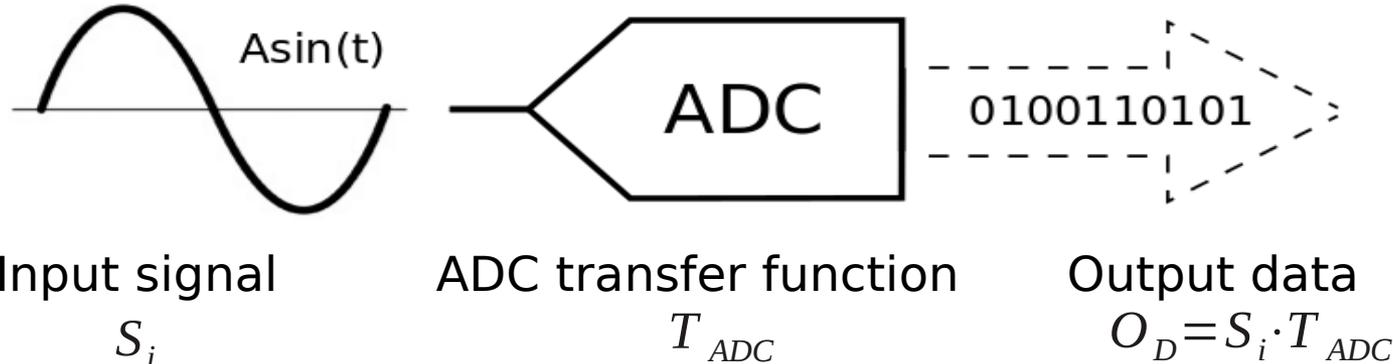
- Prototype channels fabricated to prove the performance
- Design ready for multichannel ASIC with pitch 146µm



Digital part (data transmission)

Design submitted and fabricated in 2012

ADC performance measurements: Theory of dynamic measurements



Discrete Fourier Transform (DFT) of output data

$$F(x_n): X_k = \sum_{i=0}^N x_n \exp\left(\frac{-i2\pi kn}{N}\right) \quad F(O_D) = F(S_i \cdot T_{ADC}) = F(S_i) \otimes F(T_{ADC})$$

If input signal is pure sine wave with frequency equal to the one of DFT fundamental frequencies, deconvolution is straightforward since DFT of input signal is Kronecker delta:

$$S_i = \sin(kf_{base}) \Rightarrow F(\sin(kf_{base})) = \delta_k$$

$$f_{base} = \frac{f_{sample}}{N}$$

$$F(S_i) \otimes F(T_{ADC}) = \delta_k \otimes F(T_{ADC}) = \underline{F(T_{ADC})}$$

ADC performance measurements

Theory of dynamic measurements

DFT of ADC transfer function → spectrum for given sampling frequency and input sine frequency

$$F(T_{ADC}) = f(f_{sample}, f_{sine})$$

Sampling Rate = 40.0 MHz
 Input Freq = 3.916 MHz
 Harmonics = 10

SINAD = 57.0 dB
 THD = -69.6 dB
 SNHR = 57.3 dB
 SFDR = 74.6 dB

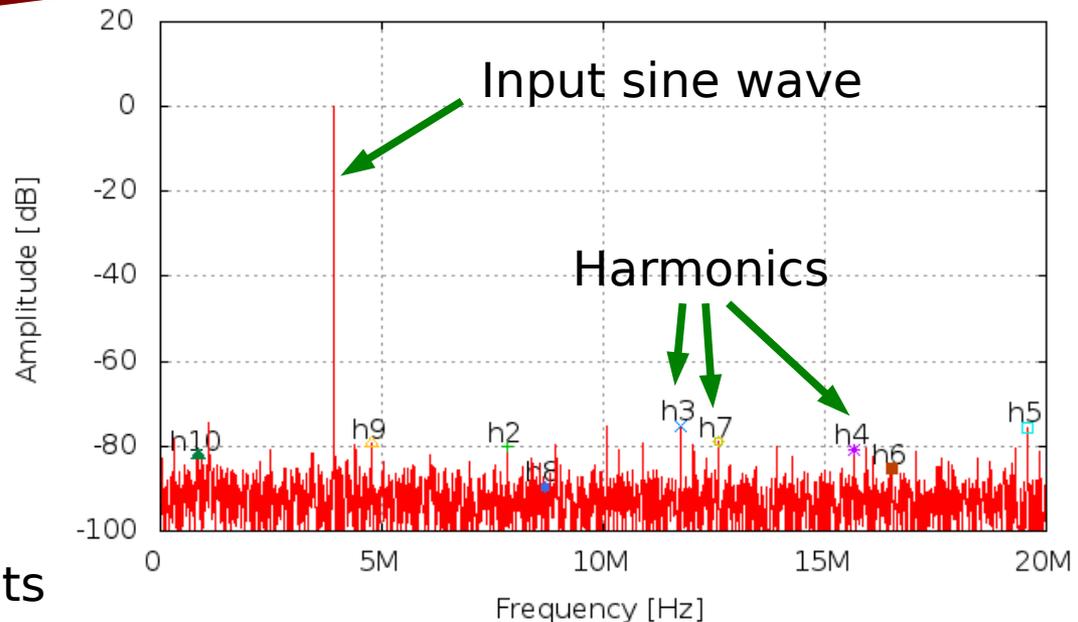
Dynamic metrics calculated from obtained DFT, i.e.:

- **SINAD** - signal to noise and distortion (harmonics) ratio

$$SINAD = 20 \log_{10} \sqrt{\frac{X_{sine}^2}{\sum_{k=1, k \neq sine}^{N/2} X_k^2}}$$

- **ENOB** - effective number of bits

$$ENOB = \frac{SINAD - 1.76}{6.02}$$



ADC performance measurements: Measurements setup - main board

DFT and data analysis -
custom software

Differential function
generator - Agilent 81160A



Power supply



Input
sine

Sample
clock

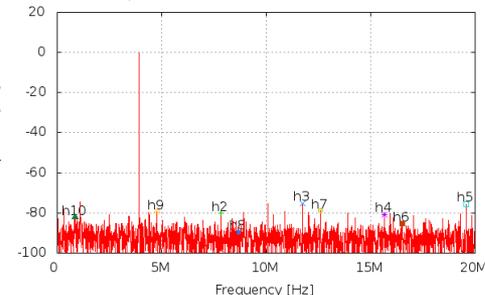
Results

Sampled data
(low bitrate)

Sampled data
(high bitrate)

Sampling Rate = 40.0 MHz
Input freq = 3.916 MHz
Harmonics = 10

SINAD = 57.0 dB
THD = -69.6 dB
SNR = 57.3 dB
SFDR = 74.6 dB



DAQ - receive fast transmission from ADC (up to 500Mb/s), store the assumed amount of data (ie. 4096 samples) and sends to PC via Ethernet for offline analysis.

ADC performance measurements: Measurement setup - main board

DAQ (VIRTEX-5 FPGA)

ADC bias and power supply

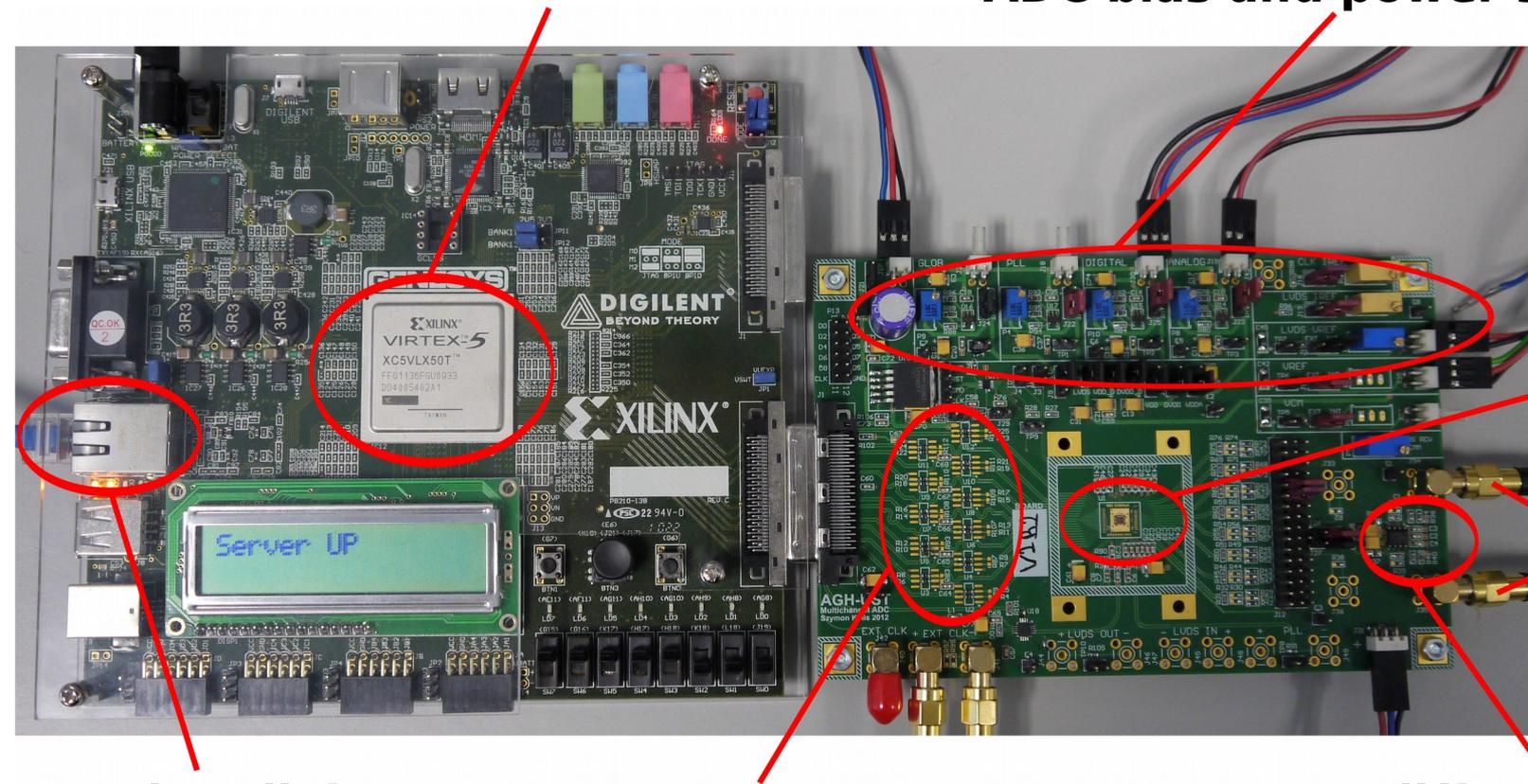
10b SAR
ADC

Input
sine

Input differential
low pass filter

PC data link
(Ethernet)

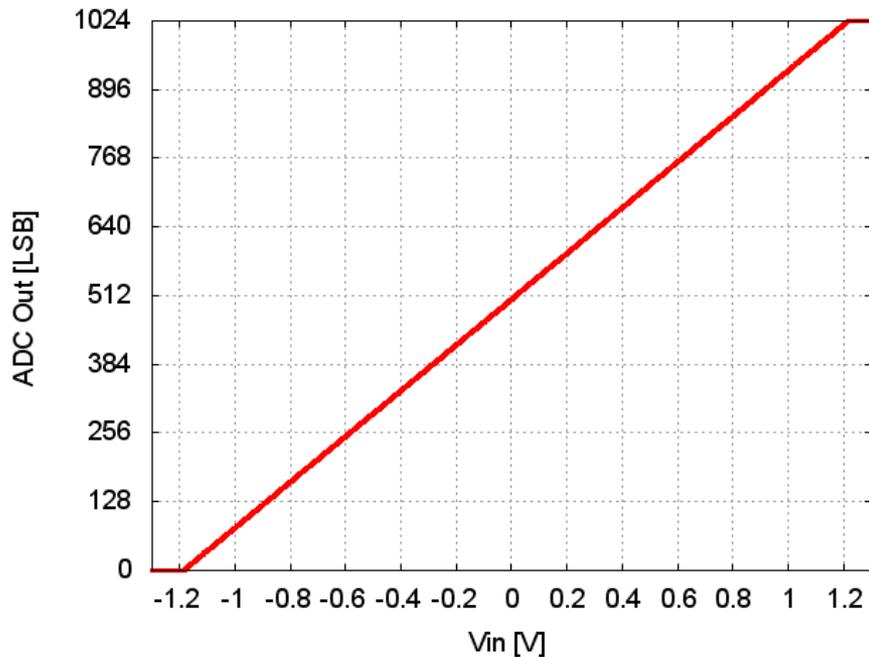
ADC output data -
parallel or serial (SLVS)



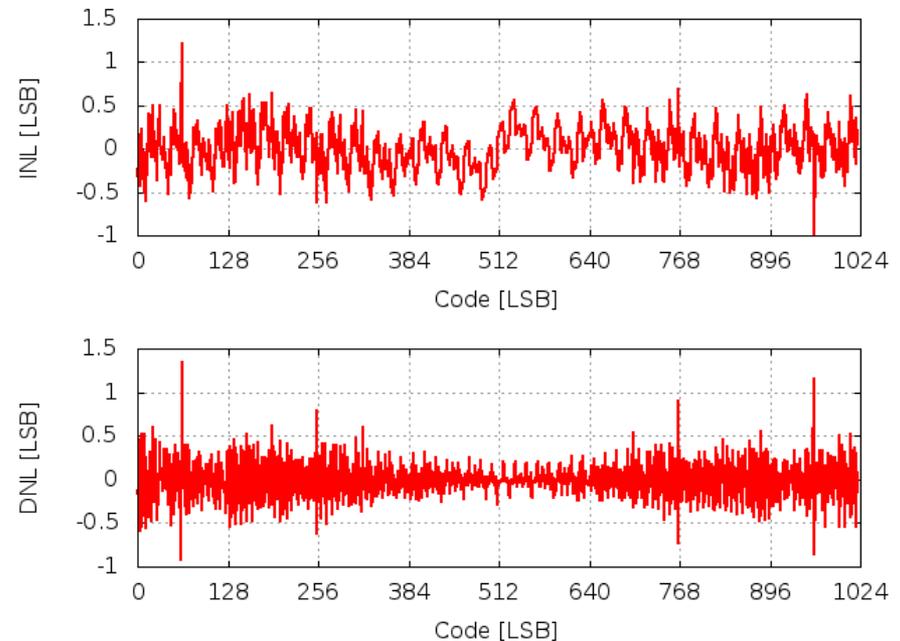
Measurements results

10-bit SAR ADC - Static measurements

Transfer function



INL/DNL measurements

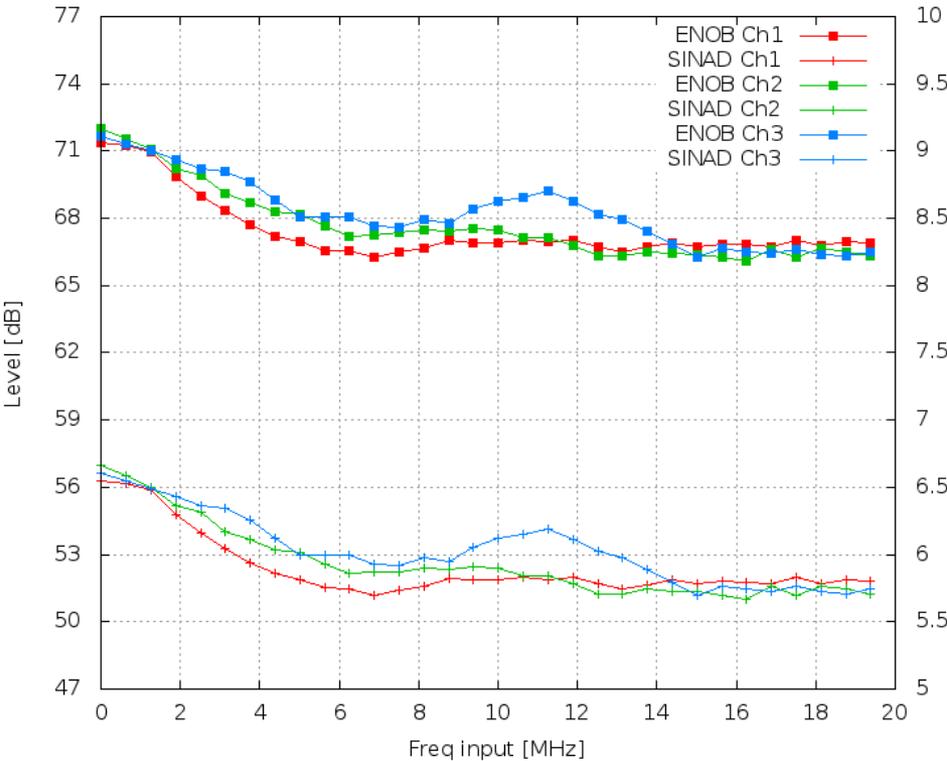
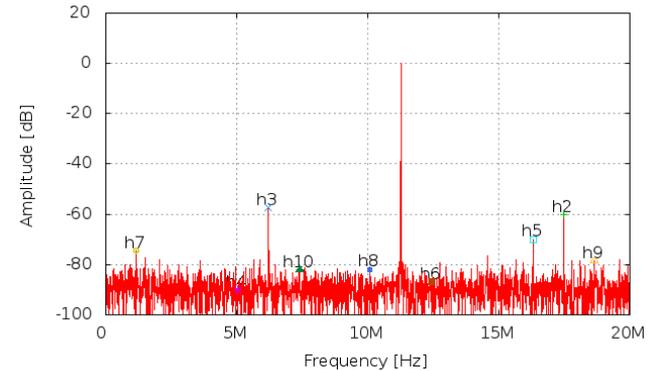


- ADC is alive and works in the whole input signal range
- There are some codes with worse linearity (some improvements in DAC layout are needed)

Measurements results: Dynamic - input and sampling frequency

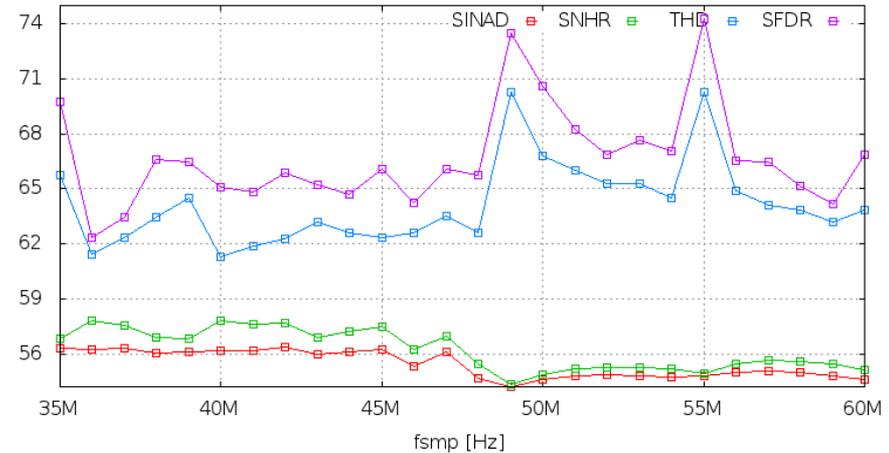
Sampling Rate = 40.0 MHz
 Input Freq = 11.260 MHz
 Harmonics = 10

SINAD = 52.1 dB
 THD = -55.4 dB
 SNHR = 54.8 dB
 SFDR = 57.4 dB



ENOB

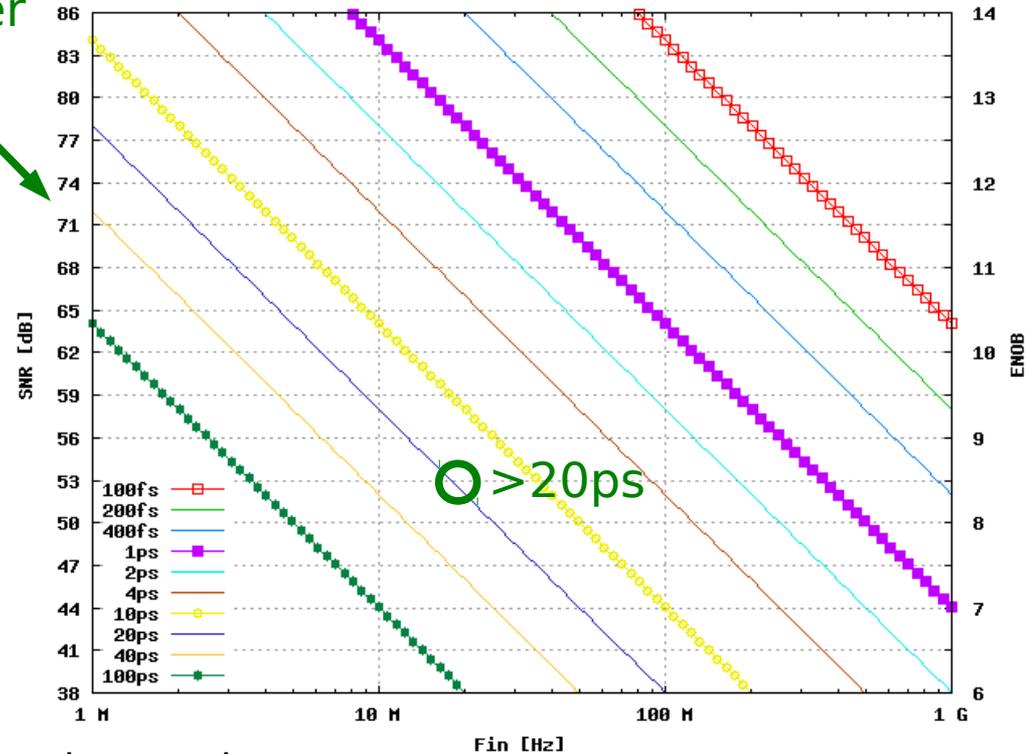
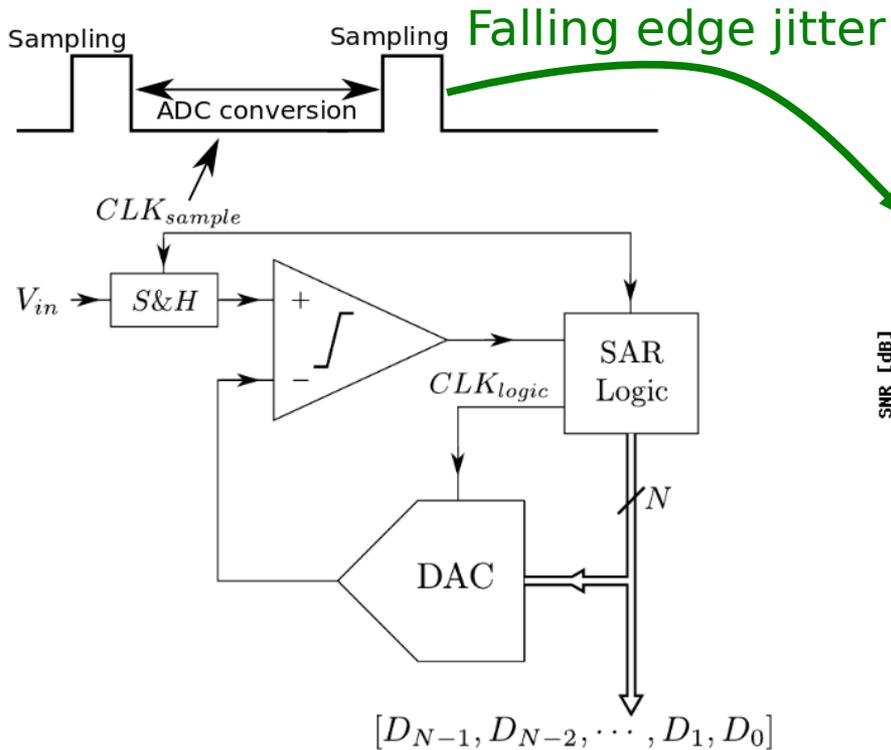
Level [dB]



- ADC works **up to about 60 MHz sampling frequency**
- ENOB decrease with input frequency - **jitter** - see next slides

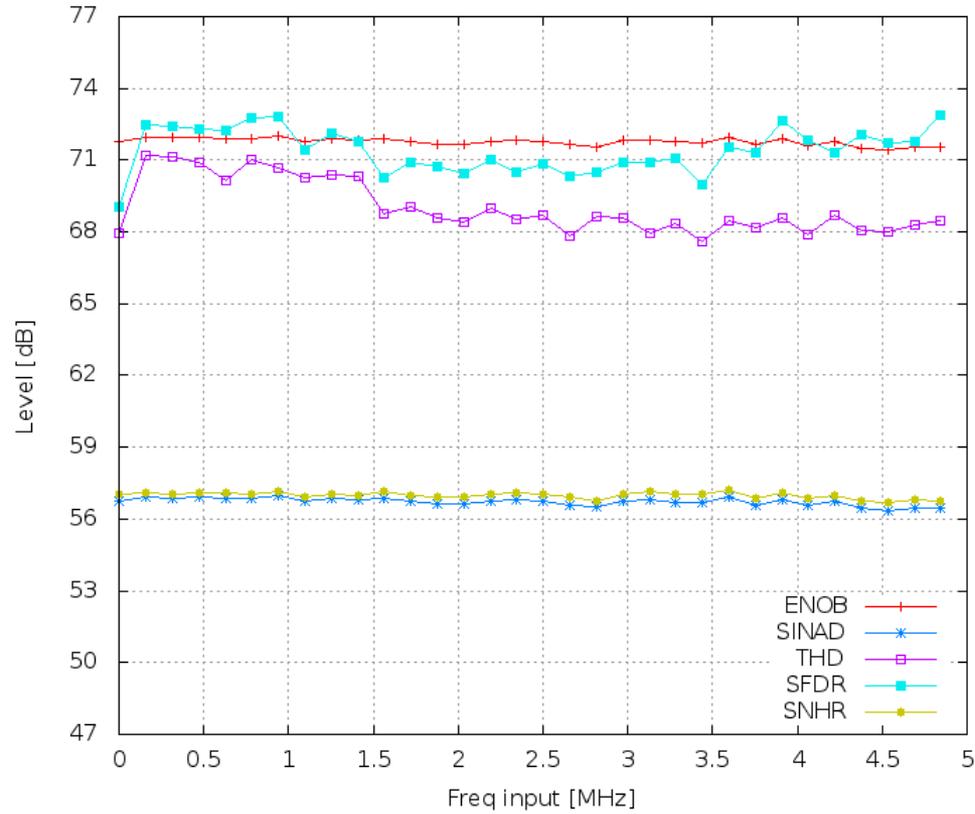
ADC performance measurements

Resolution vs sampling clock jitter...



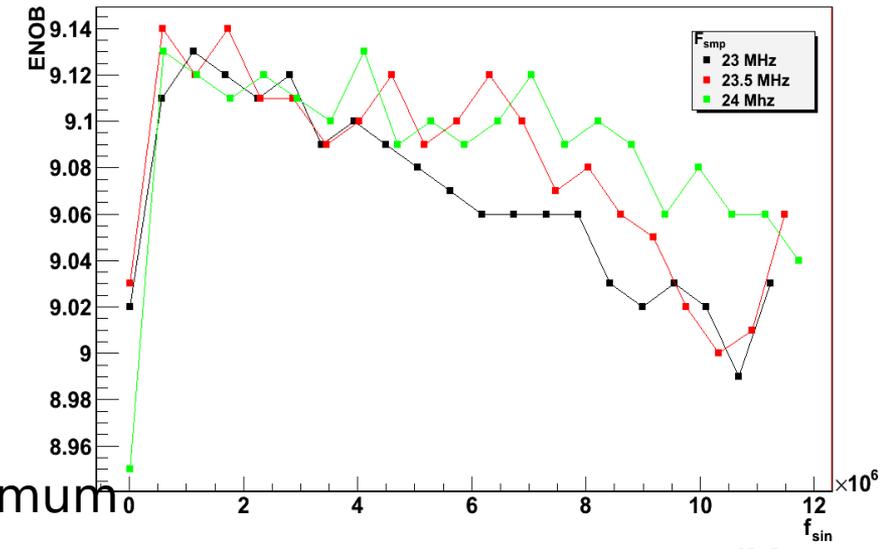
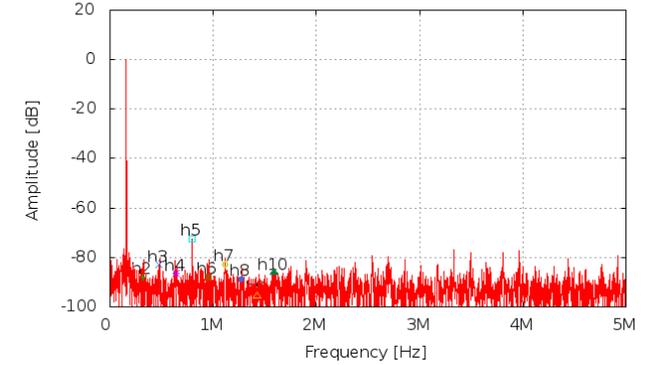
- Sampling time steered by triggering pulse duty cycle
- Non-50% duty cycle triggering pulse generated by internal circuit → introducing jitter – although post-layout simulations showed very small jitter, in reality it was larger than expected → it caused worsening of the ENOB
- + Temporary solution – use 50% duty cycle external clock (low jitter) as triggering pulse
- Max. ADC sampling frequency dropped below 25 MHz

Measurements results: Dynamic measurements - clock improvement



Sampling Rate = 10.0 MHz
 Input Freq = 158.691 kHz
 Harmonics = 10

SINAD = -56.9 dB
 THD = -71.2 dB
 SNHR = 57.1 dB
 SFDR = 72.5 dB

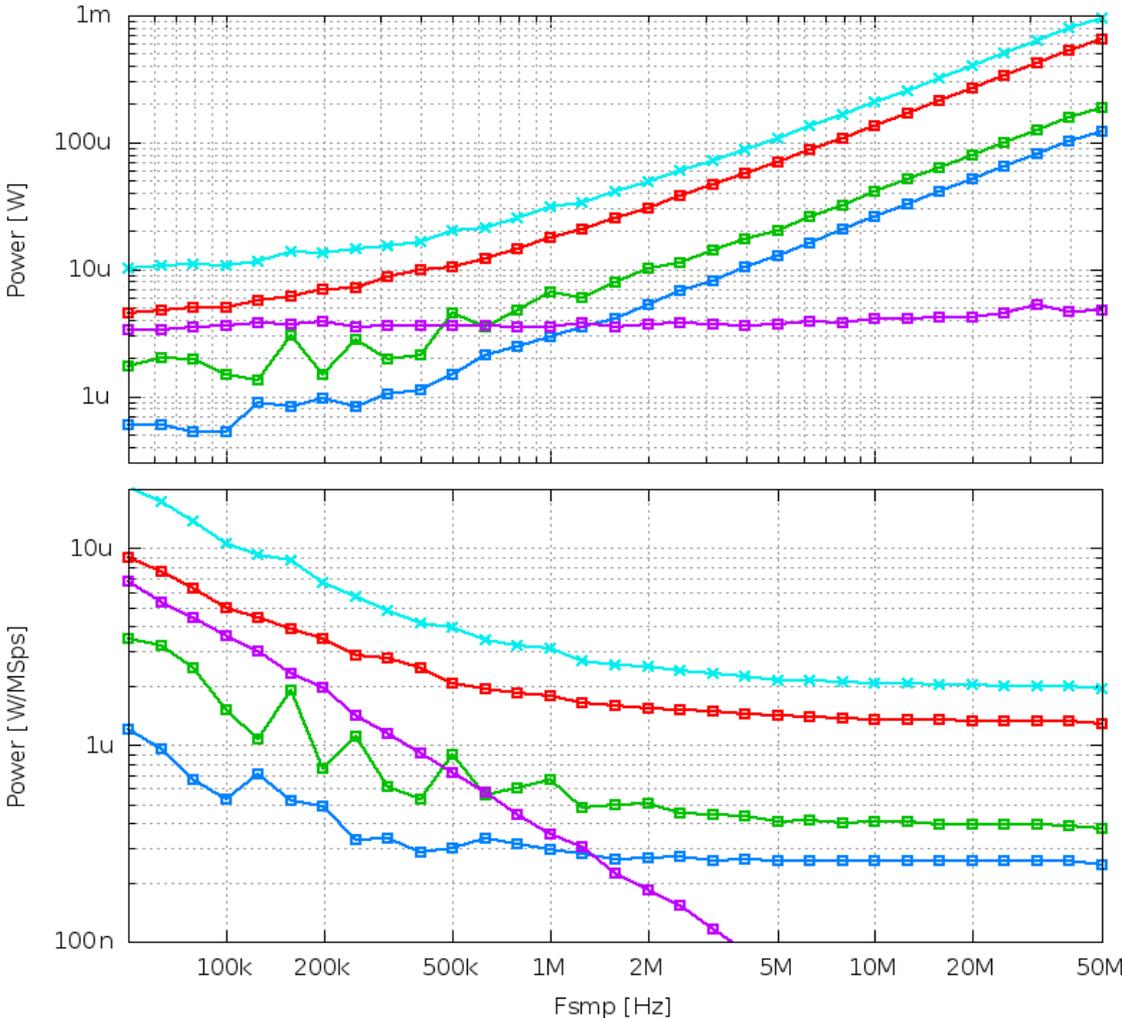


• Clock improvement allows to obtain **ENOB > 9.2** up to Nyquist, lowering maximum sampling frequency below 25 MS/s

Measurements results

Power consumption vs sampling frequency

Digital  Analog  IREF  ICM  Total 



- Power consumption is about **1 mW per channel at 40 MS/s** - in agreement with simulations

- Fully dynamic SAR ADC with asynchronous logic was designed and fabricated
- ADC power consumption varies proportionally to sampling frequency (up to 60MHz)
- Power pulsing comes for free in the chosen architecture
- Effective resolution ENOB ~ 9.2 bit for sampling frequencies below 25 MHz, for higher frequencies ENOB drops to ~ 8.5 bit due to large jitter
- At 40 MHz sampling frequency ultra low power of $\sim 1\text{mW}$ was obtained
- Linearity and resolution worse than simulated
- Too large jitter of sampling pulse

Will be addressed in next submission... Together with all multichannel aspects